

FIG. 1A, Example repetitive array image

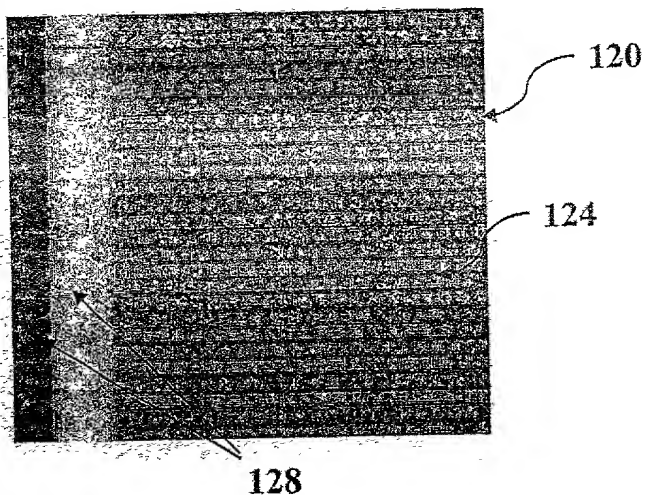
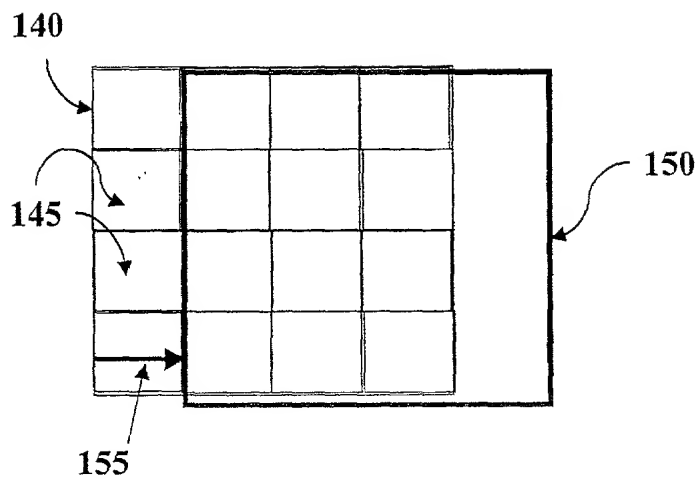


FIG. 1B, Example image with repetitive and non-repetitive areas.

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**FIG. 1C, Inspection of repetitive regions
(Prior Art)**

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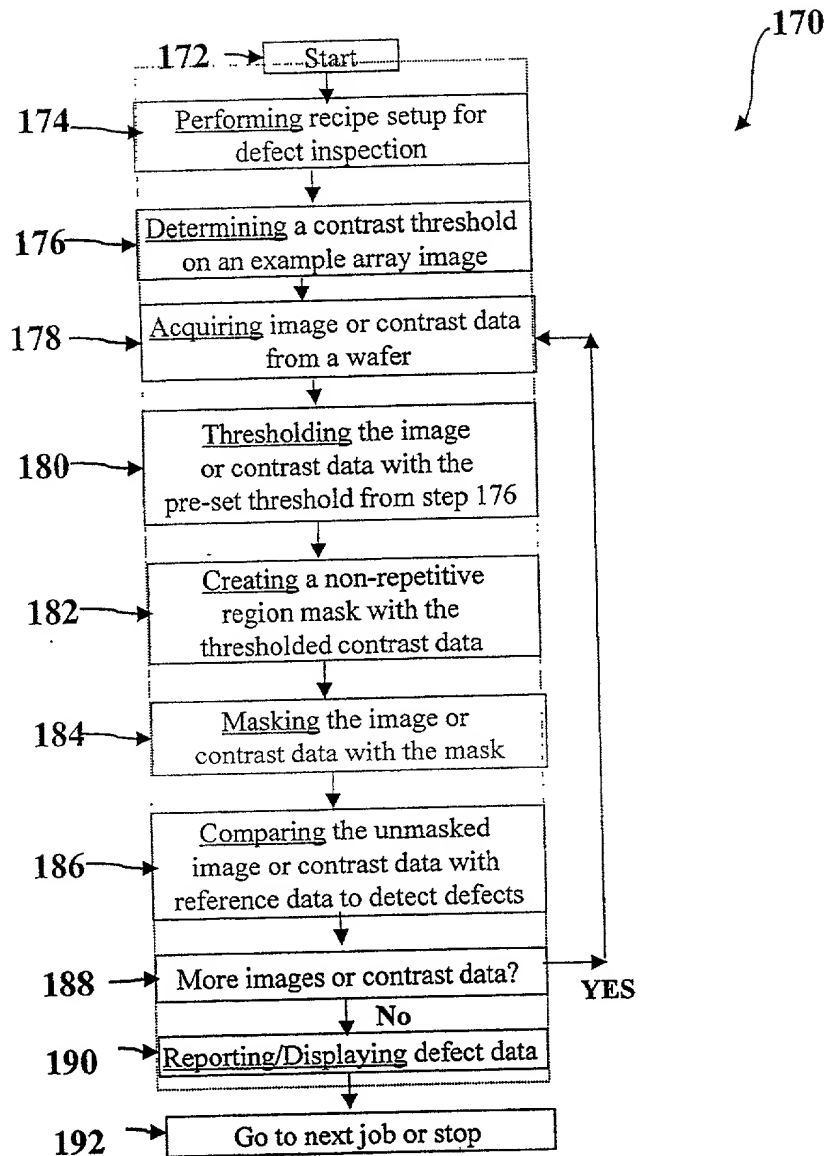


Fig 1D. Thresholding contrast data method

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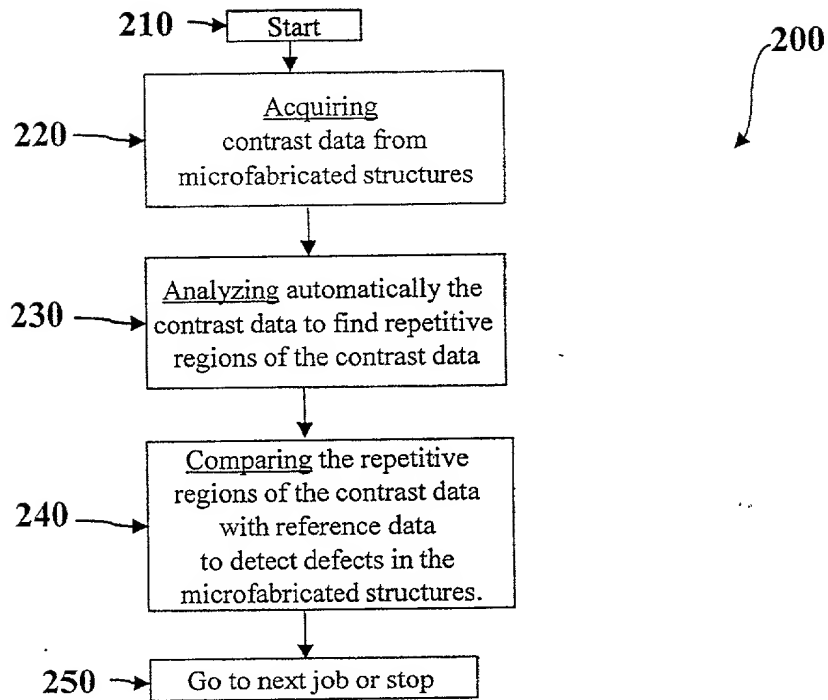
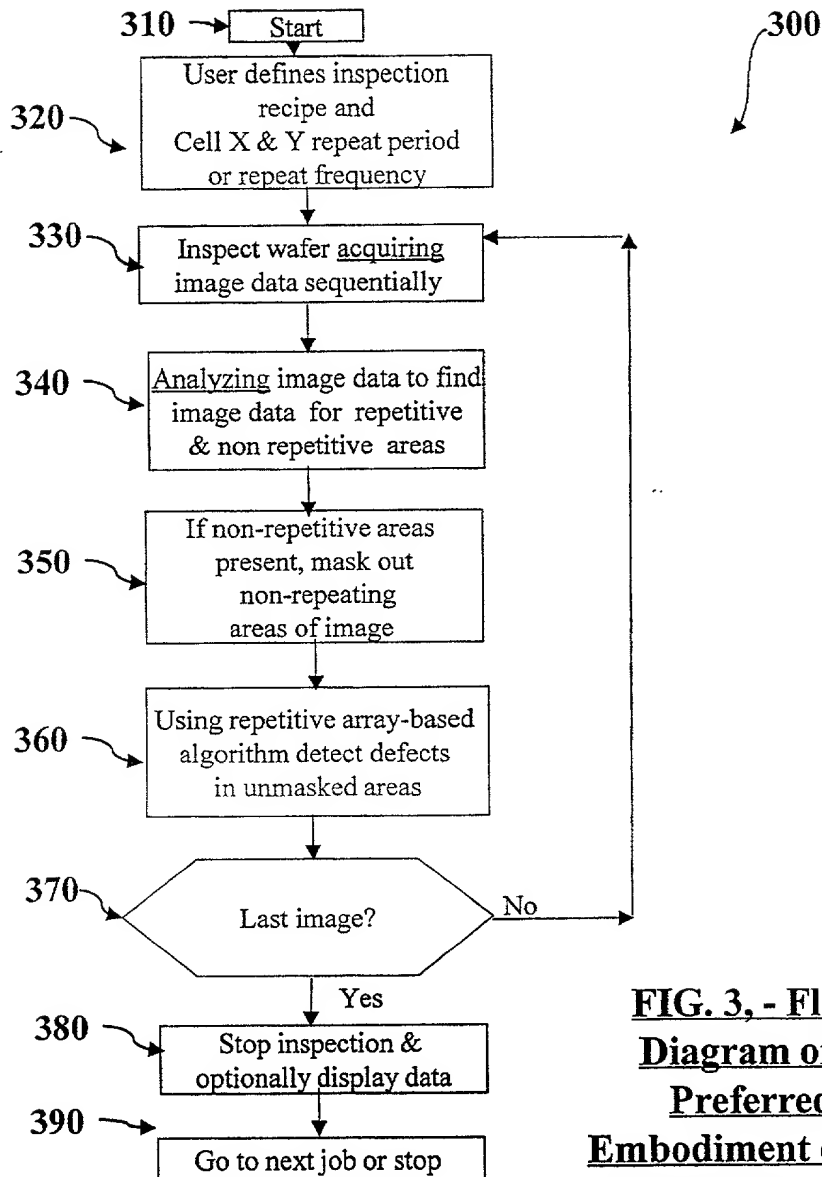


Fig 2.

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**FIG. 3, - Flow
Diagram of a
Preferred
Embodiment of the
Present Invention**

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FIG. 4A

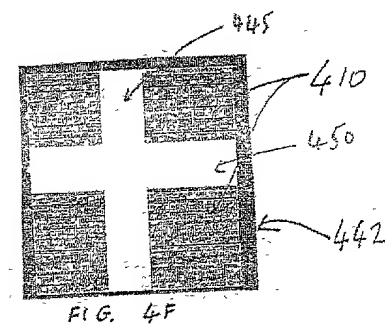
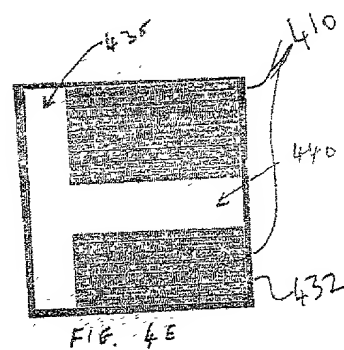
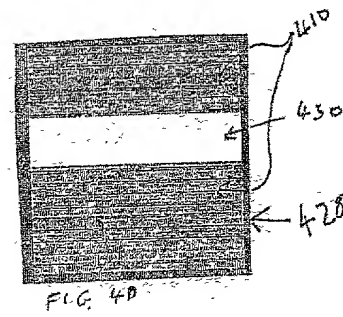
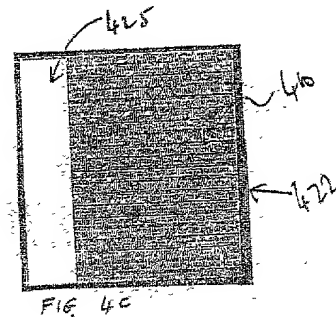
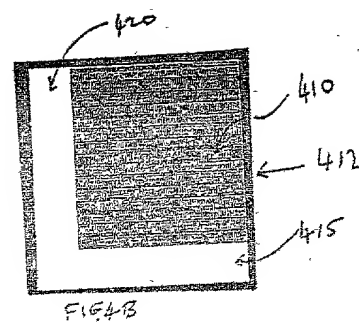
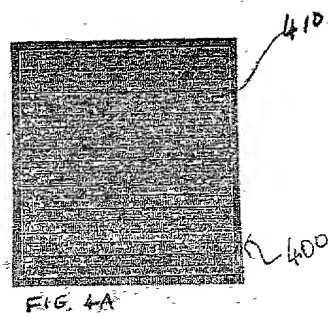
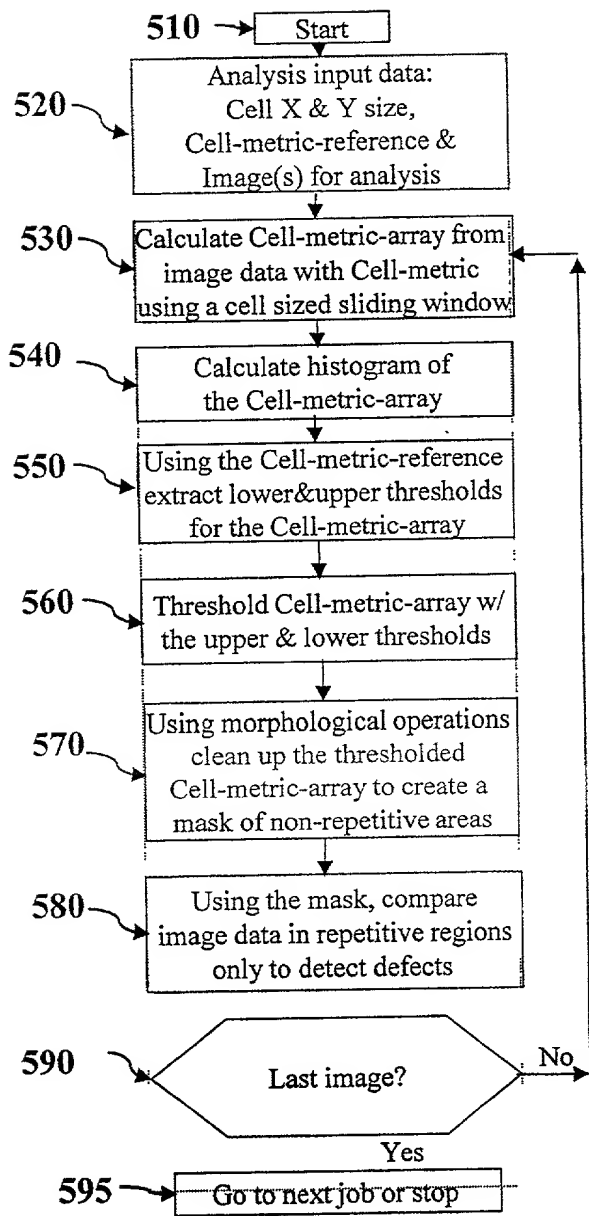


Fig 4a-f - Example Images with repetitive array areas and adjacent non-repetitive areas

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**FIG. 5, - Flow
Diagram of method
of image analysis
to find repetitive
regions**

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FIG. 6A

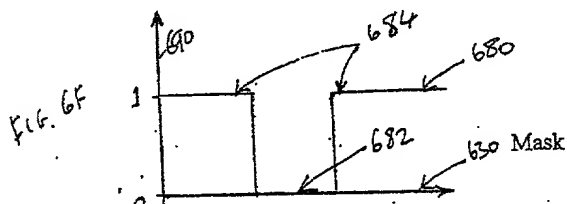
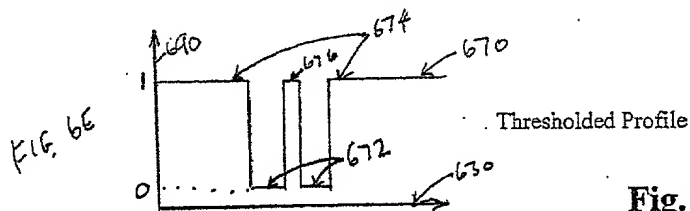
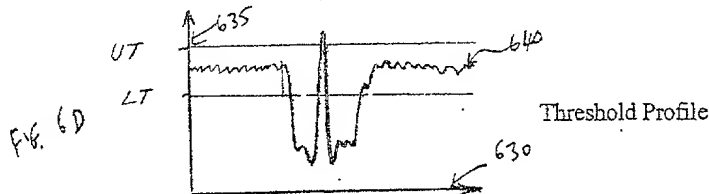
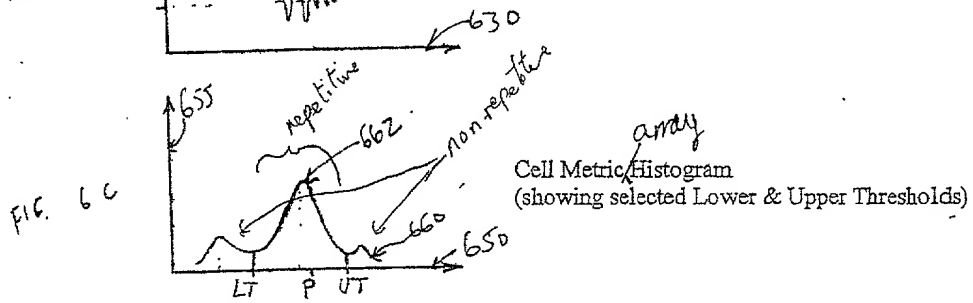
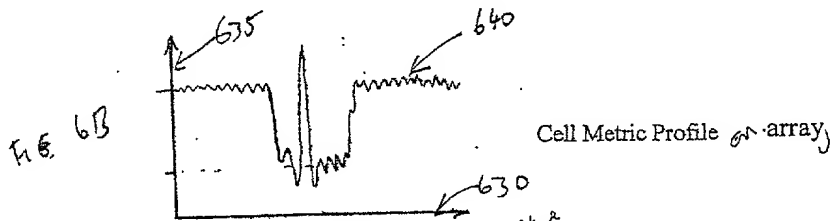
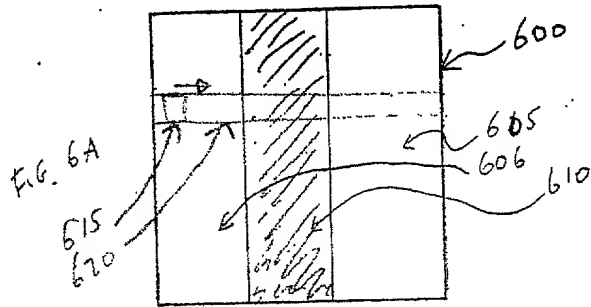


Fig. 6 - Diagrammatic example of analysis data flow

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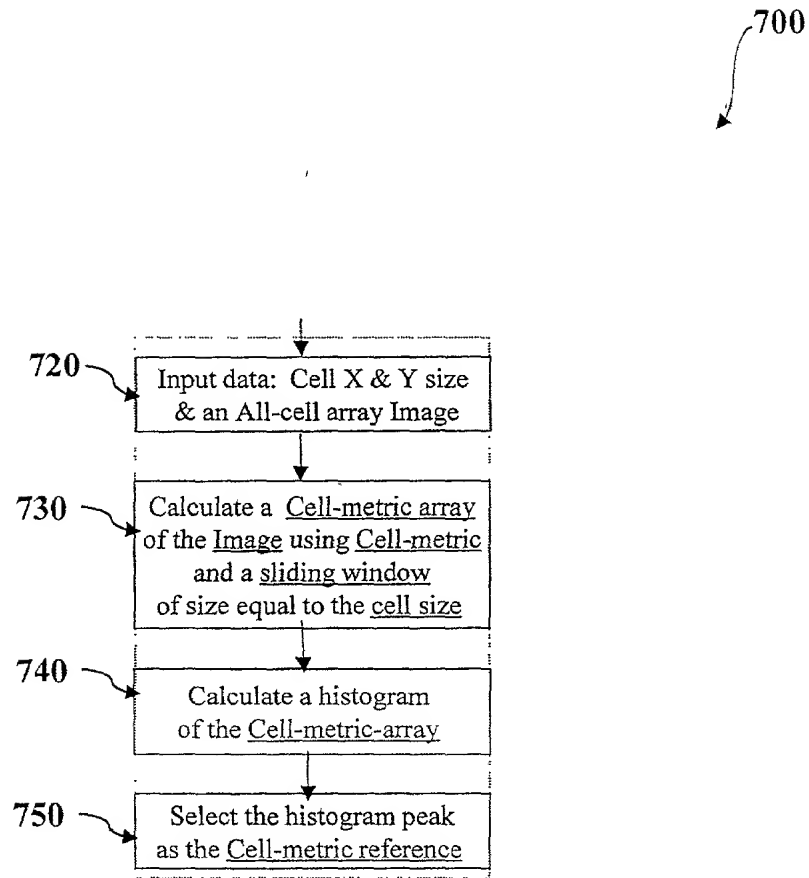


Fig. 7 Method to calculate Cell Metric Reference

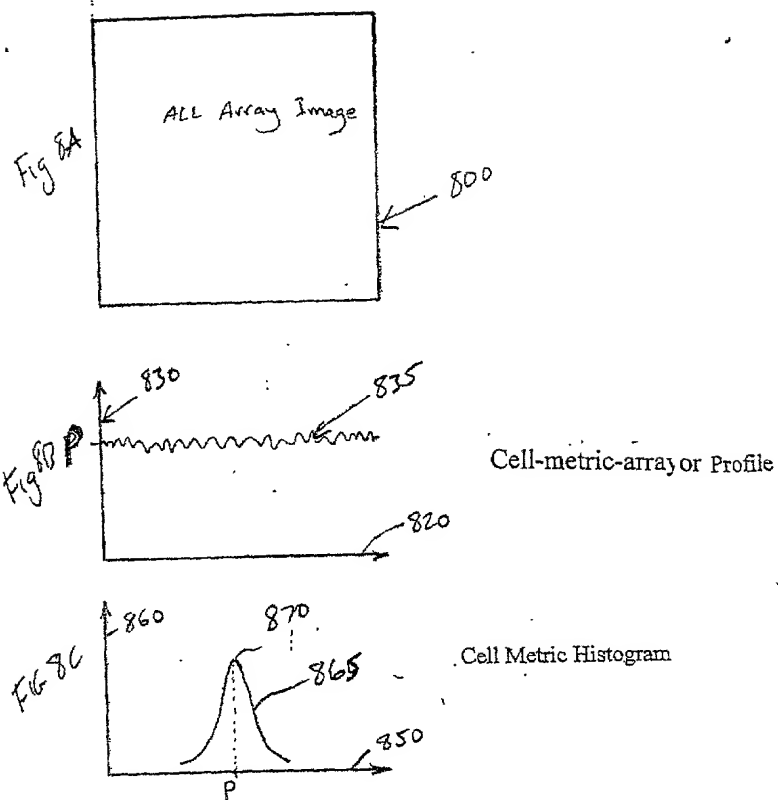


Fig. 8 Example of Cell-metric reference calculation

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FIG. 9A - Dual profile approach

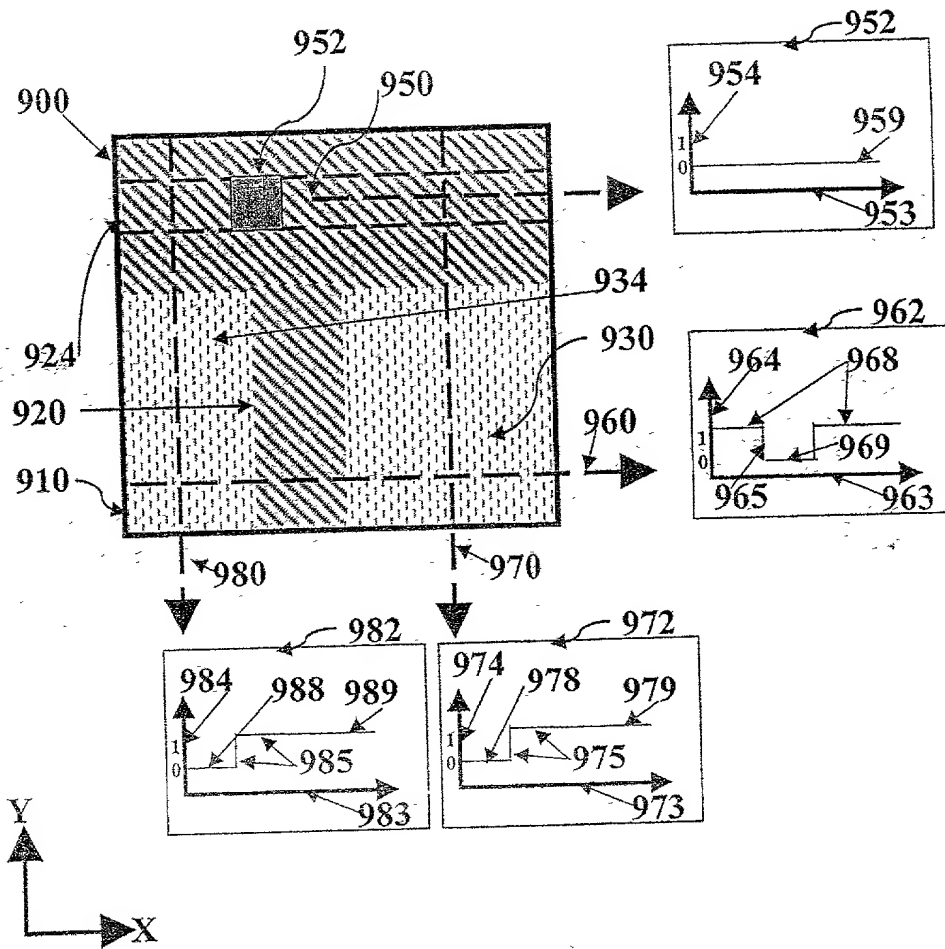


Fig. 9A - Dual profile approach

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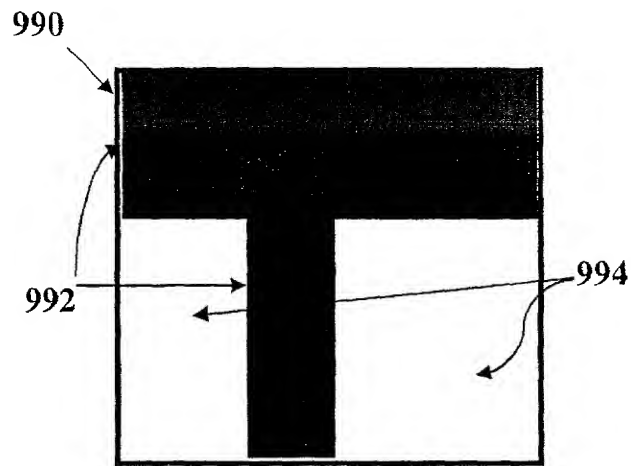


Fig 9B - mask created from the dual line-profiles

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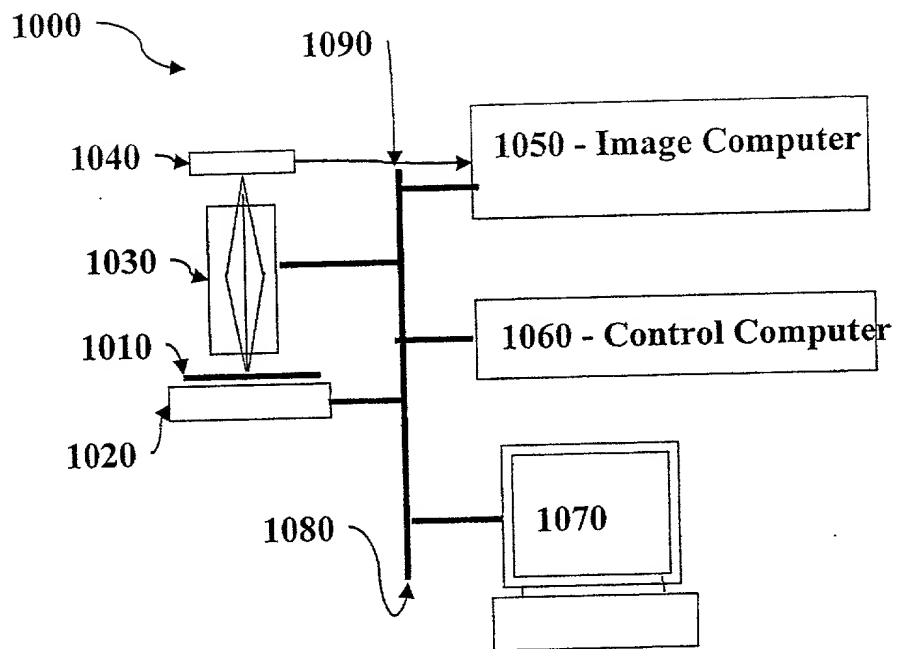


Fig. 10, System Block Diagram

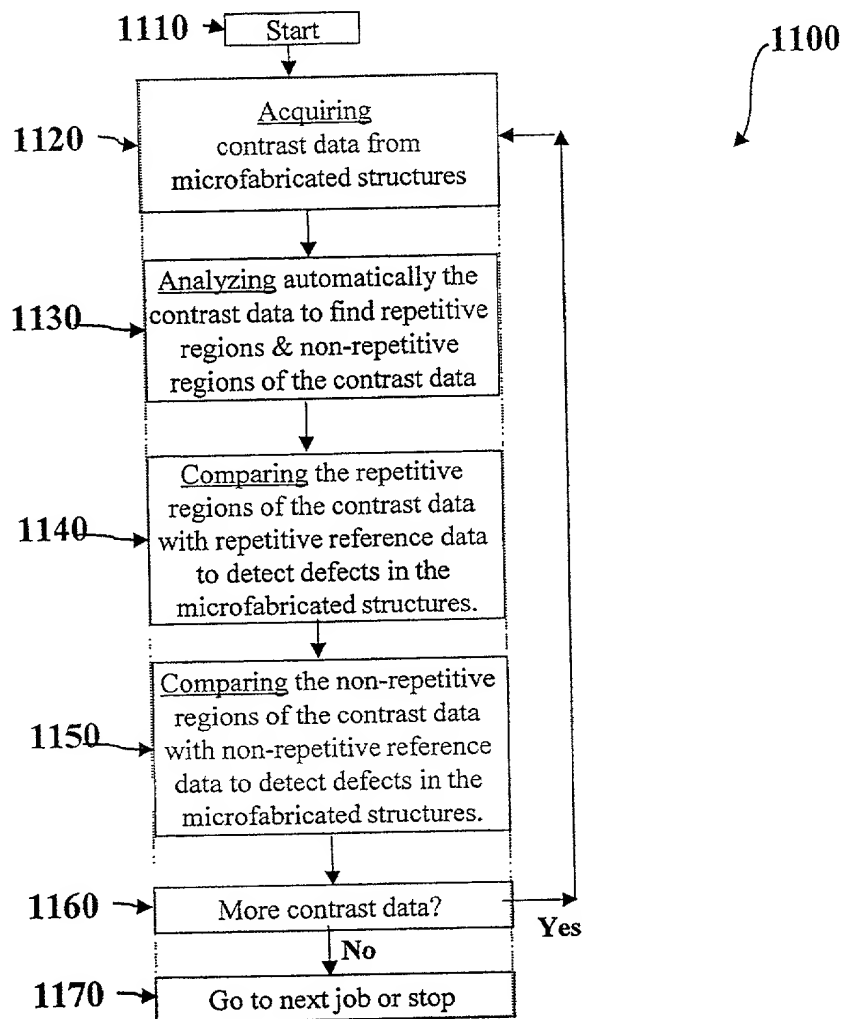


FIG. 11 - Flow for inspecting both repetitive and non-repetitive areas with a single pass

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